

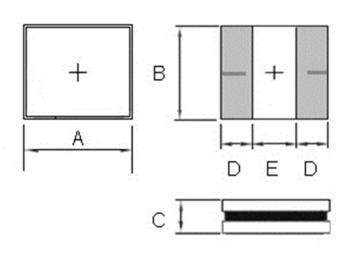
### **FEATURES**

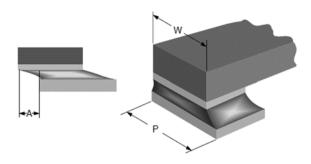
- Low profile
- Low DCR
- Large Current Adaptable
- High Frequency(up to 1MHz)

### **APPLICATIONS**

- Laptop Computer / Notebook Computer
- Graphic Card/ VGA Module
- DC/DC converter or VRM applications
- Thin type on-board power supply module for exchanger
- Inductor for general purpose use

## CONFIGURATIONS & DIMENSIONS (unit in mm)





#### Overhang acceptance description

Side overhang (A) is less than or equal to 20% width ofcomponent termination area (W) or 20% width of land (P)whichever is less.

Series	Α	В	С	D	E
HAP252012	$2.5 \pm 0.3$	$2.0 \pm 0.35$	1.3 MAX	0.85 REF	0.80 REF



### **Electrical characteristics**

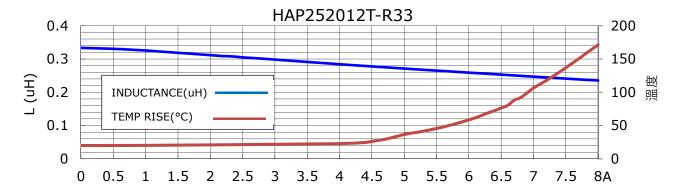
Part Number	Inductance	Test Frequency	DCR	DCR	I sat	I sat	I rms	I rms
	(uH)	(Hz)	(Ω) typ.	(Ω) Max.	(A) typ.	(A) Max.	(A) typ	(A) Max.
HAP252012T-R33M	0.33±20%	1M	0.022	0.032	6.80	6.5	4.7	4.3
HAP252012T-R47M	0.47±20%	1M	0.025	0.035	6.30	6.0	4.3	4.0
HAP252012T-1R0M	1.0±20%	1M	0.047	0.055	4.80	4.5	3.5	3.2
HAP252012T-1R5M	1.5±20%	1M	0.065	0.072	4.10	3.8	2.7	2.4
HAP252012T-2R2M	2.2±20%	1M	0.09	0.108	3.30	3.1	2.4	2.3
HAP252012T-3R3M	3.3±20%	1M	0.14	0.165	2.60	2.4	2.2	2.0
HAP252012T-4R7M	4.7±20%	1M	0.20	0.30	2.20	2.10	2.00	1.90
HAP252012T-100M	10±20%	1M	0.45	0.55	1.40	1.30	1.10	1.00

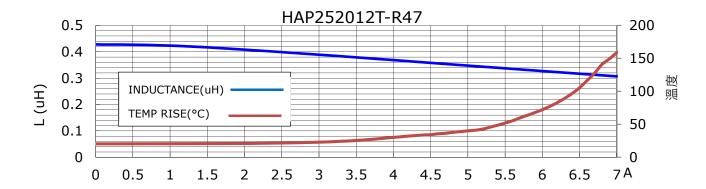
#### Notes

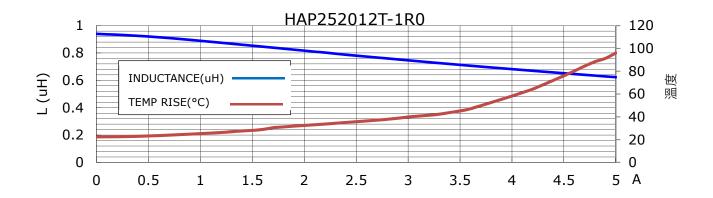
- 1.All test data is referenced to 25 °C ambient
- 2.Operating temperature range 40 °C to + 125 °C
- 3.Idc(A):DC current (A) that will cause an approximate  $\Delta T$  of 40 °C (reference ambient temperature is 25 °C)
- 4.Isat(A):DC current (A) that will cause L0 to drop approximately 30 %
- 5.If Use wave soldering is there will be some risk.(Crack \u00aunwitting& Mark Shedding).
- 6.Re-flow soldering temperatures below 240 degrees, there will be unwitting risk.
- 7. When total area of exposed wire occurring to each sides is not greater than 75% of coating resin area, that is acceptable.

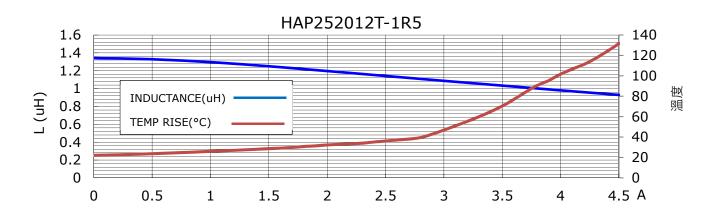


### **CURRENT CHARACTERISTICS**

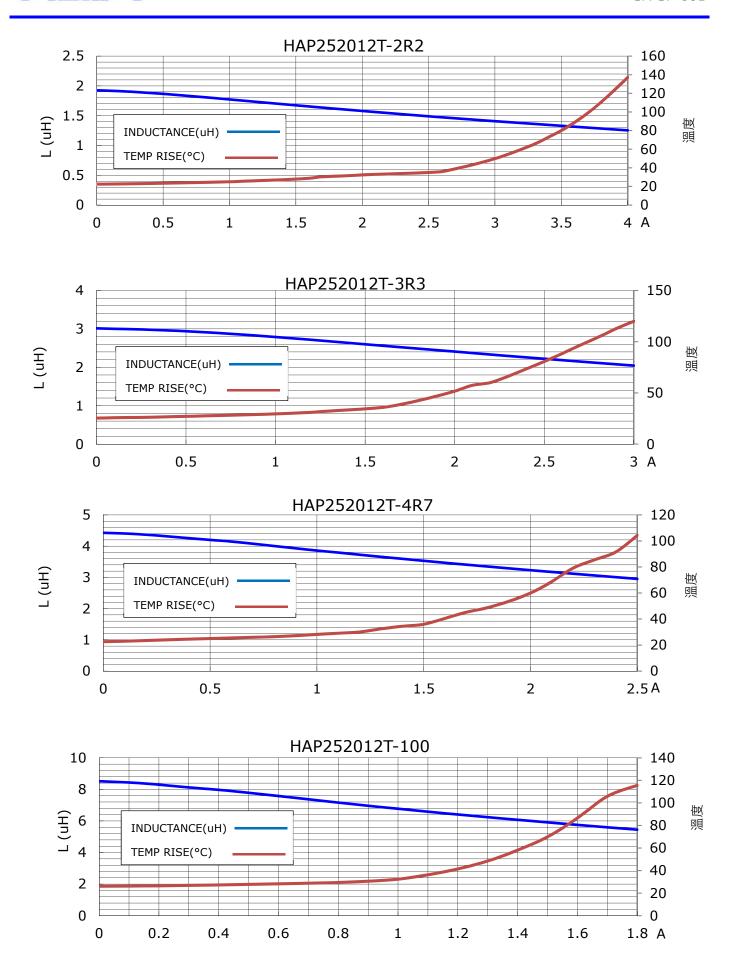








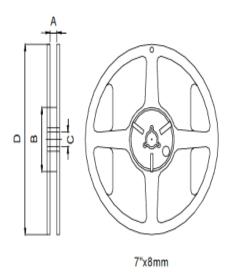




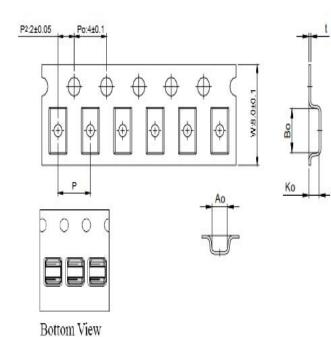


# **Packaging Information**

## **Reel Dimension**



Туре	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	8.4±1.0	50 min.	13±0.8	178±2



Series	Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
PIN	252012	2.85±0.1	2.40±0.1	1.35±0.1	4.0±0.1	0.23±0.05

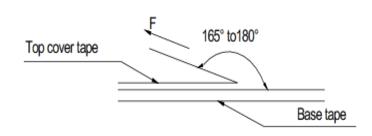


### **Packaging Information**

## **Packaging Quantity**

Chip size	252012
Chip / Reel	2000

## **Tearing Off Force**



The force for tearing off cover tape is 15 to 80 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed
(℃)	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

## Storage Conditions

To maintain the solderability of terminal electrodes:

- 1. products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- Temperature and humidity conditions: Less than 40<sup>o</sup> and 60<sup>o</sup> RH.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
  - 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
  - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
  - 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



# **Reliability and Test Condition**

Item	Performance	Test Condition						
Operating temperature	-40~+105℃ (Including self - temperature rise)							
Storage temperature	110~+40°ℂ,50~60%RH (Product with taping) 240~+105°ℂ (on board)							
Electrical Performance Test								
Inductance	Prince the standard of the sta	HP4284A,CH11025,CH3302,CH1320,CH1320S LCR Meter.						
DCR	Refer to standard electrical characteristics list.	CH16502,Agilent33420A Micro-Ohm Meter.						
Saturation Current (Isat)	Approximately∆L30%	Saturation DC Current (Isat) will cause L0 to drop △L(%)						
Heat Rated Current (Irms)	Approximately △T40°C	Heat Rated Current (Irms) will cause the coil temperature rise $\triangle T(C)$ . 1.Applied the allowed DC current 2.Temperature measured by digital surface thermometer						
Reliability Test								
Life Test		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles)  Temperature: 125±2°C (Inductor)  Applied current: rated current  Duration: 1000±12hrs  Measured at room temperature after placing for 24±2 hrs						
Load Humidity		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity: 85±2 * R.H,  Temperature: 85°C±2°C  Duration: 1000hrs Min. with 100% rated current  Measured at room temperature after placing for 24±2 hrs						
Moisture Resistance	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles 1. Baked at50°C for 25hrs, measured at room temperature after placing for 4 hrs. 2. Raise temperature to $65\pm2°C$ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to $25°C$ in 2.5hrs. 3. Raise temperature to $65\pm2°C$ 90-100%RH in 2.5hrs, and keep 3 hours, cool down to $25°C$ in 2.5hrs. 4 hours, cool down to $25°C$ in 2.5hrs heep at $-10°C$ for 3 hrs 4. Keep at $25°C$ 80-100%RH for 15min and vibrate at the frequency of 10 to $55°C$ to 10 Hz, measure at room temperature after placing for 1~2 hrs.						
Thermal shock  Vibration		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: $-40\pm2^{\circ}\mathbb{C}$ 30 $\pm5$ min Step2: $25\pm2^{\circ}\mathbb{C} \leq 0.5$ min Step3: $125\pm2^{\circ}\mathbb{C} \leq 0.5$ min Step3: $125\pm2^{\circ}\mathbb{C} \leq 0.5$ min Number of cycles: 500 Measured at room temperature after placing for $24\pm2$ hrs Oscillation Frequency: $10 \sim 2$ K $\sim 10$ Hz for 20 minutes Equipment: Vibration checker						
		Total Amplitude:1.52mm±10% Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations).						
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805 inch(2012mm):40x100x1.2mm <0805 inch(2012mm):40x100x0.8mm Bending depth: >=0805 inch(2012mm):1.2mm <0805 inch(2012mm):0.8mm duration of 10 sec.						
Shock	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Type         Peak value (g's)         Normal duration (D) (ms)         Wave form (vi)ft/sec         Velocity change (vi)ft/sec           SMD         50         11         Half-sine         11.3           Lead         50         11         Half-sine         11.3						
Solder ability	More than 95% of the terminal electrode should be covered with solder.	Preheat: 150°C,60sec.。 Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5°C ∘						



		Flux for lead free: Rosin. 9.5% ∘
		Dip time: 4±1sec ∘
		Depth: completely cover the termination
		Depth: completely cover the termination
Resistance to Soldering Heat		Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate Number of heat cycles
		260 ±5 (solder temp) 10 ±1 25mm/s ±6 mm/s 1
Terminal Strength	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value e	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force(>0805:1kg, <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested.

Note: When there are questions concerning measurement result: measurement shall be made after  $48 \pm 2$  hours of recovery under the standard condition.